OBVERSE/REVERSE DISCRIMINATIVE RECTANGULAR
NITRIDE SEMICONDUCTOR WAFER

ABSTRACT OF THE DISCLOSURE

A mirror-polished obverse surface and a roughened reverse surface of the

5   conventional GaN wafers have been discriminated by difference of roughness on the surfaces

with human eyesight.   The difference of the surfaces is rather ambiguous.   Cracks/breaks

and distortion of the wafers have been likely to occur because the roughness of the reverse

surface is apt to bring fine particles.

To discern an obverse from a reverse without making use of the difference of the

10   surface roughness, the present invention provides an obverse/reverse discriminative

rectangular nitride semiconductor wafer having a longer slanting edge and a shorter slanting

edge at obversely-clockwise neighboring corners, or having an asymmetric slanting edge at a

corner, or having asymmetrically bevelled parts or having discriminating characters marked

by laser.   The present invention can make the reverse surface mirror-polished and smooth, so

15   that particles on the reverse surface and distortion, cracks or breaks of the wafer decrease.